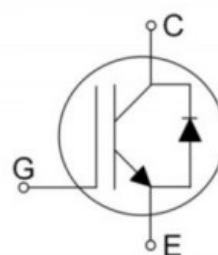
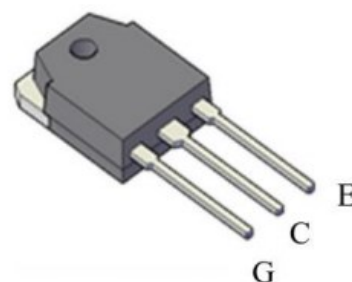


FEATURES

- High breakdown voltage up to 650V for improved reliability
- Trench-Stop IGBT Technology offering :
 - High speed switching
 - High ruggedness, temperature stable
 - Short circuit withstand time – 5μs
 - Low V_{CEsat}
 - Easy parallel switching capability due to positive temperature coefficient in V_{CEsat}

V_{CE}	650	V
I_C	65	A
$V_{CE(SAT)} \quad I_C=65A$	1.6	V



APPLICATION

- Uninterruptible Power Supplies
- Inverter
- Welding Converters
- PFC applications
- Converter with high switching frequency

Product	Package	Packaging
YGD65N65U1	TO-3P	Tube

Maximum Ratings (T_j= 25°C unless otherwise specified)

Parameter	Symbol	Value	Unit
Collector-Emitter Breakdown Voltage T _j ≥ 25°C	V _{CE}	650	V
DC collector current, limited by T _{jmax} T _C = 25°C T _C = 100°C	I _C	130 65	A
Diode Forward current, limited by T _{jmax} T _C = 25°C T _C = 100°C	I _F	40 20	A
Continuous Gate-emitter voltage	V _{GE}	±20	V
Transient Gate-emitter voltage (t _p ≤ 10μs, D < 0.01)	V _{GE}	±30	V
Turn off safe operating area V _{CE} ≤ 650V, T _j ≤ 175°C, t _p = 1μs	-	195	A
Pulse collector current, V _{GE} = 15V, t _p limited by T _{jmax}	I _{CM}	195	A
Diode Pulsed Current, t _p limited by T _{jmax}	I _{Fpuls}	60	A
Short Circuit Withstand Time, V _{GE} = 15V, V _{CE} ≤ 400V	T _{SC}	5	μs
Power dissipation, T _j = 25°C	P _{tot}	272	W
Operating junction temperature	T _j	-40...+175	°C
Storage temperature	T _s	-55...+150	°C
Soldering temperature, wave soldering 1.6mm (0.063in.) from case for 10s	-	260	°C
Mounting torque, M3 screw Maximum of mounting processes: 3	M	0.6	Nm

Thermal Resistance

Parameter	Symbol	Max. Value	Unit
IGBT thermal resistance, junction - case	R _{θ(j-c)}	0.55	K/W
Diode thermal resistance, junction - case	R _{θ(j-c)}	1.95	K/W
Thermal resistance, junction - ambient	R _{θ(j-a)}	48	K/W

Electrical Characteristics (T_j= 25°C unless otherwise specified)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Static						
Collector-Emitter Breakdown Voltage	BV _{CES} ①	V _{GE} =0V, I _C =250μA	650	-	-	V
Gate Threshold Voltage	V _{GE(th)}	V _{GE} =V _{CE} , I _C =250μA	4.4	5.2	6.0	V
Collector-Emitter Saturation Voltage	V _{CE(sat)}	V _{GE} =15V, I _C =65A T _j = 25°C T _j = 175°C	- -	1.6 2.1	2.0 -	V
Zero gate voltage collector current	I _{CES}	V _{CE} = 650V, V _{GE} =0V T _j = 25°C T _j = 175°C	- -	-	100 5000	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V, V _{GE} =±20V	-	-	400	nA
Transconductance	g _{fs}	V _{CE} = 20V, I _C = 65A	-	45	-	S
Diode Forward Voltage	V _{FM}	I _F = 20A	-	1.4	-	V

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Dynamic						
Input capacitance	C _{ies}	V _{CE} = 25V, V _{GE} = 0V, f = 1MHz	-	4820	-	pF
Output capacitance	C _{oes}		-	365	-	
Reverse transfer capacitance	C _{res}		-	35	-	
Gate charge	Q _G	V _{CC} = 520V, I _C = 65A, V _{GE} = 15V	-	138	-	nC
Short circuit collector current	I _{C (SC)}	V _{GE} =15V, t _{SC} ≤5μs V _{CC} =400V, T _j =25°C	-	500	-	A

Note:

BV_{CES} testing without filter could damage the device. BV_{CES} is guaranteed by I_{CES}@650V test.

Switching Characteristic, Inductive Load

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Dynamic T _j =25°C						
Turn-on Delay Time	t _{d(on)}	V _{CC} =400V, I _C =65A, V _{GE} = 0/15V, R _g =10Ω	-	40	-	ns
Rise Time	t _r		-	87	-	ns
Turn-off Delay Time	t _{d(off)}		-	150	-	ns
Fall Time	t _f		-	80	-	ns
Turn-on Energy	E _{on}		-	1.8	-	mJ
Turn-off Energy	E _{off}		-	1.6	-	mJ
Dynamic T _j =150°C						
Turn-on Delay Time	t _{d(on)}	V _{CC} =400V, I _C =65A, V _{GE} = 0/15V, R _g =10Ω	-	45	-	ns
Rise Time	t _r		-	92	-	ns
Turn-off Delay Time	t _{d(off)}		-	170	-	ns
Fall Time	t _f		-	100	-	ns
Turn-on Energy	E _{on}		-	1.9	-	mJ
Turn-off Energy	E _{off}		-	1.8	-	mJ

Fig. 1 Saturation voltage characteristics

$$I_C = f(V_{CE})$$

$$V_{GE} = 15V$$

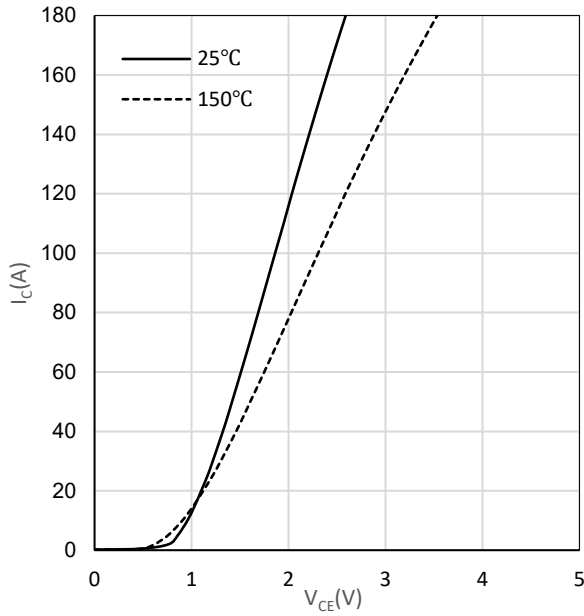


Fig. 2 Output characteristics

$$I_C = f(V_{CE})$$

$$T_J = 25^\circ C$$

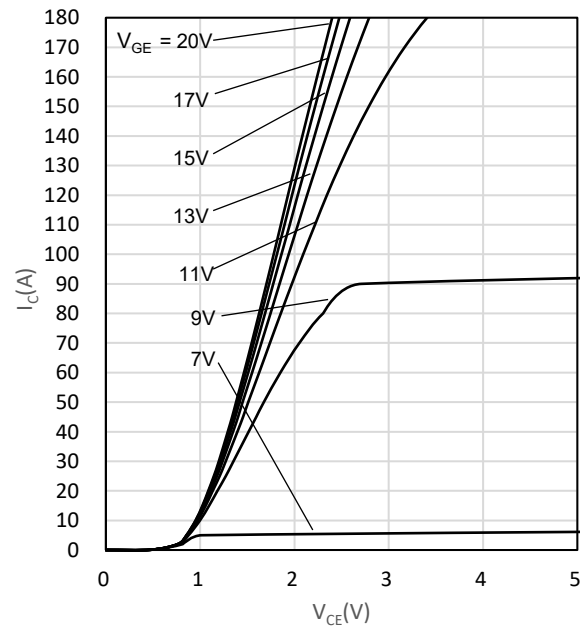


Fig. 3 Transfer characteristic

$$I_C = f(V_{GE})$$

$$V_{CE} = 20V$$

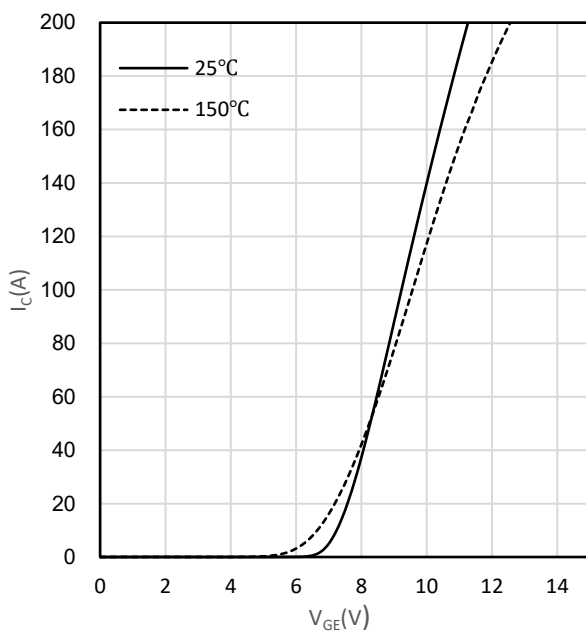


Fig. 4 Switching losses IGBT

$$E_{on} = f(I_C), E_{off} = f(I_C)$$

$$V_{GE} = 0-15V, R_G = 10\Omega, V_{CE} = 400V, T_J = 150^\circ C$$

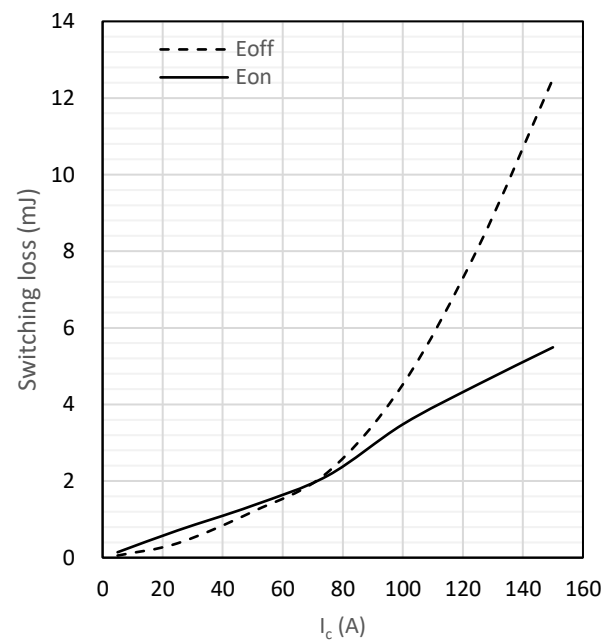


Fig. 5 Switching losses IGBT

$E_{on}=f(R_g)$, $E_{off}=f(R_g)$
 $V_{GE}=0-15V$, $I_C=65A$, $V_{CE}=400V$, $T_J=150^\circ C$

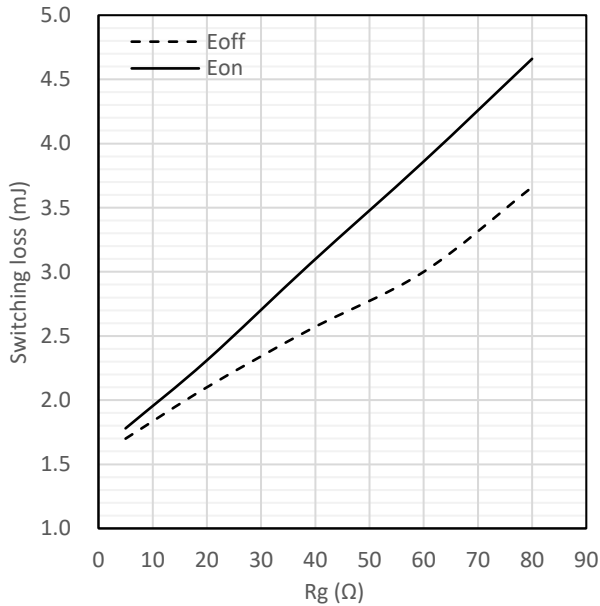


Fig. 6 Switching times IGBT

$T_{don}=f(I_C)$, $T_r=f(I_C)$, $T_{doff}=f(I_C)$, $T_f=f(I_C)$
 $V_{GE}=0-15V$, $R_g=10\Omega$, $V_{CE}=400V$, $T_J=150^\circ C$

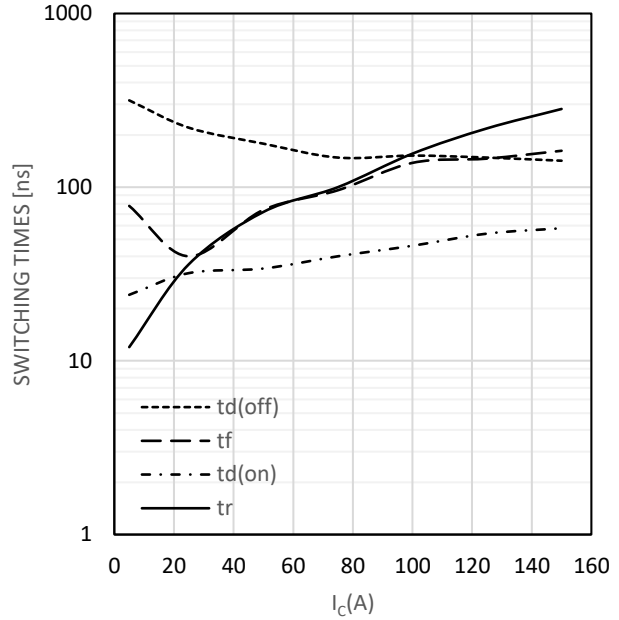


Fig. 7 Switching times IGBT

$T_{don}=f(R_g)$, $T_r=f(R_g)$, $T_{doff}=f(R_g)$, $T_f=f(R_g)$
 $V_{GE}=0-15V$, $I_C=65A$, $V_{CE}=400V$, $T_J=150^\circ C$

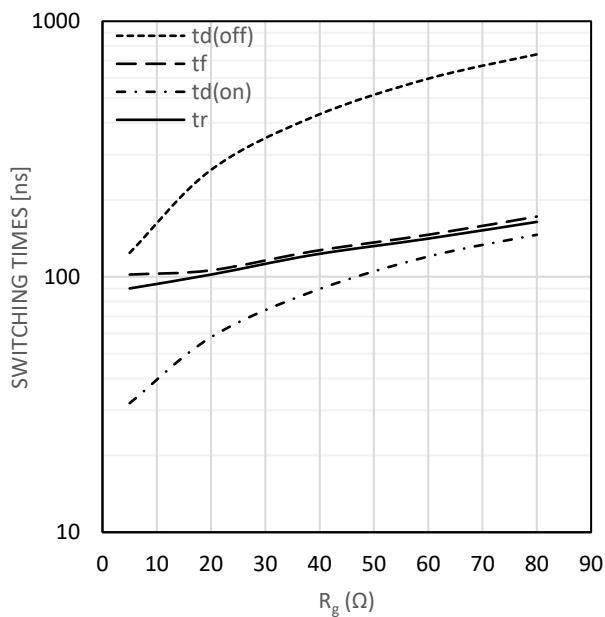


Fig. 8 Gate charge characteristics

$V_{GE}=f(Q_g)$
 $I_C=65A$, $T_J=25^\circ C$

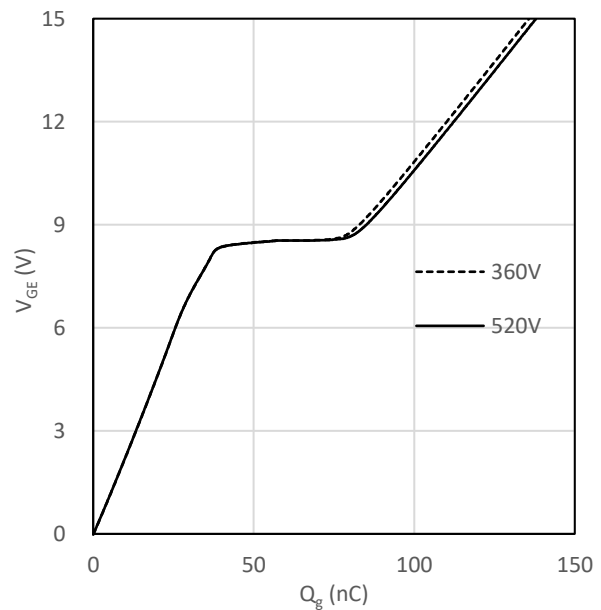


Fig. 9 Capacitance characteristics

$C_{ies}=f(V_{CE})$, $C_{oes}=f(V_{CE})$, $C_{res}=f(V_{CE})$
 $T_J=25^{\circ}\text{C}$

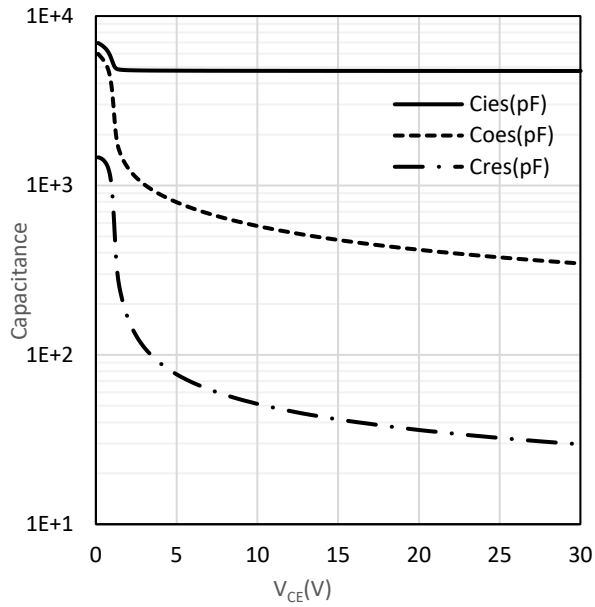
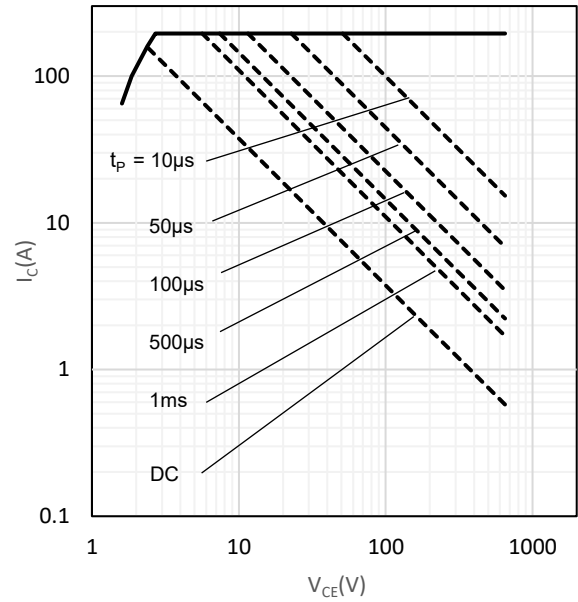
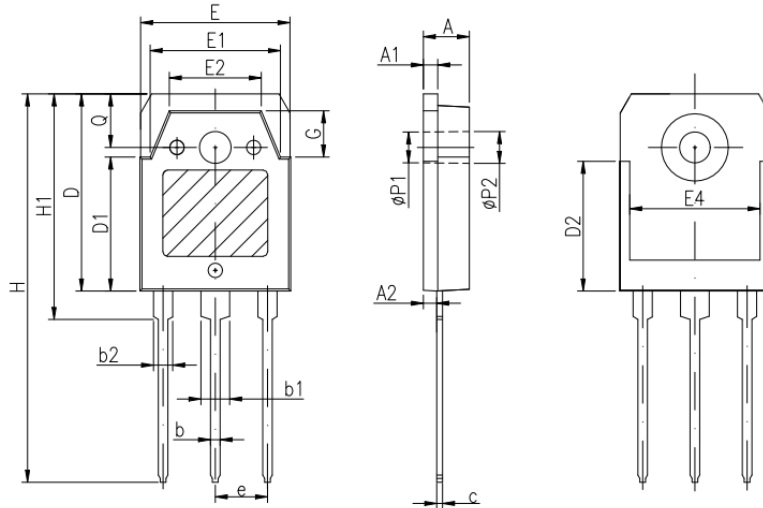


Fig. 10 Forward bias safe operating area

$I_C=f(V_{CE})$
 $D=0$, $T_C=25^{\circ}\text{C}$, $T_J \leq 175^{\circ}\text{C}$; $V_{GE}=15\text{V}$



TO-3P package information



COMMON DIMENSIONS

SYMBOL	mm		
	MIN	NOM	MAX
A	4.60	4.80	5.00
A1	1.40	1.50	1.65
A2	1.18	1.38	1.58
b	0.80	1.00	1.20
b1	2.80	3.00	3.20
b2	1.80	2.00	2.20
c	0.50	0.60	0.75
D	19.60	19.90	20.20
D1	13.55	13.90	14.25
D2		12.90	REF
E	15.35	15.60	15.85
E1	13.40	13.60	13.80
E2	9.40	9.60	9.80
E4	12.60	-	-
e		5.45	TYP
G	4.55	4.80	5.05
H	40.10	40.50	40.90
H1	23.15	23.40	23.65
ØP1	3.03	3.20	3.37
ØP2	3.30	3.50	3.70
Q	5.00 REF		

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